

Notice of References Cited

Application/Control No.

10/039,333

Applicant(s)/Patent Under
Reexamination
LEE ET AL.

Examiner

Binh X Tran

Art Unit

1765

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	M	US-			

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	N	EP 0837497 A2	04-1998	European	Kumar, Ajay	H 01L 21/321
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NON-PATENT DOCUMENTS

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